Applied Machine Learning in NIR Technology

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Deadline for manuscript submissions:
closed (15 March 2022)

Message from the Guest Editors

Dear Colleagues,

The aim of this Special Issue is to present the latest advances that have been made in this field, combining both techniques, as well as to show the remaining challenges and the future in this area of research.

The Special Issue solicits submissions in, but not limited to, the following areas:

Selection of features or bands of the NIR spectra, with a special interest in those applications using nano-scale NIR scanners due to its limit operational range;

Studies of different preprocessing techniques and comparison with automatic features extraction process, such as PCA, LDA, evolutionary computation;

Developments combining cloud computing, fog computing or edge computing with the processing of NIR spectra in different industrial processes;

Application and comparative of the latest approaches of machine learning techniques, such as deep learning or ensemble models;

Works with a particular interest to cover the explainable artificial intelligence in the frame of decision-making using NIR data and machine learning.

Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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